

Keysight Technologies

Modifying DDR Libraries for Silicon Nail Test Generation on the x1149 Boundary Scan Analyzer

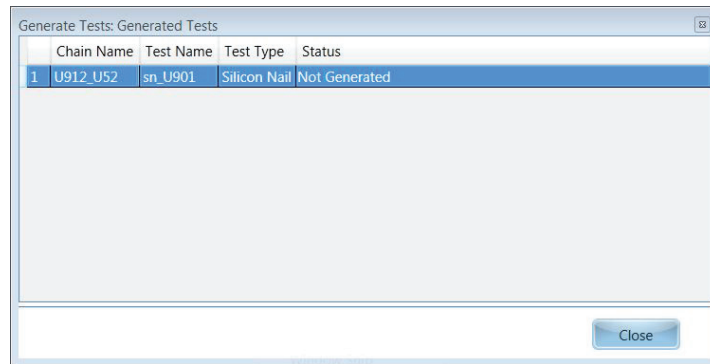
Application Note



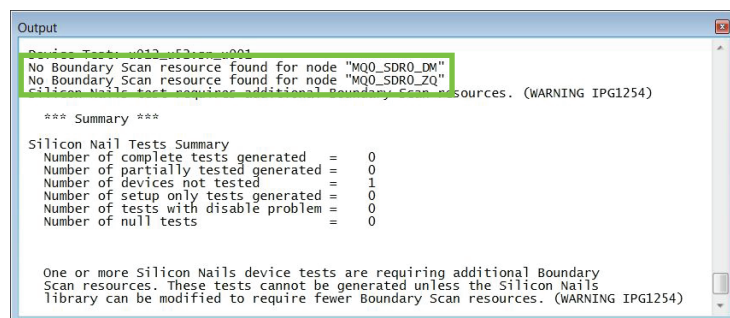
The DDR libraries available are written with the assumption that all the pins are connected to a boundary scan cell. In a real board application however, there are pins that are not connected to boundary scan cells, in which case we will need to modify the DDR library to generate the silicon nail test.

Here are the step-by-step procedures on DDR library modification and silicon nail test generation.

1. When silicon nail test is not generated during the Keysight Technologies, Inc. x1149 test:

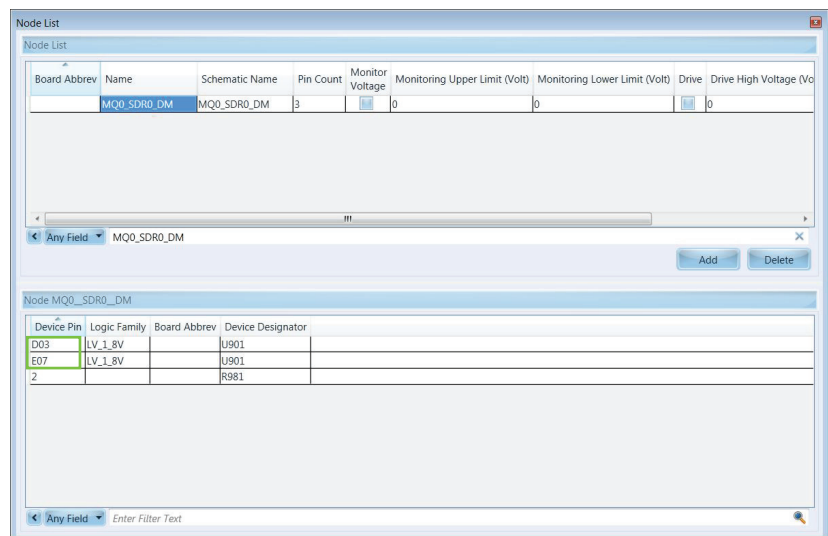


2. Check the output message:



The output message shows that the following nodes "MQ0_SDR0_DM" and "MQ0_SDR0_ZQ" are not connected to a boundary scan cell or resource.

3. Check the board details to find out if the "MQ0_SDR0_DM" and "MQ0_SDR0_ZQ" are connected to a DDR and the boundary scan device pins.



4. The node "MQ0_SDR0_DM" in the node list shows the DDR pins D03 and E07 are shorted and connected to resistor "R981" and the pull down is set to "GND".
5. Do the same for the other node "MQ0_SDR0_ZQ", which is connected to resistor "R971", with the pull down set to "GND".
6. The nodes "MQ0_SDR0_DM" and "MQ0_SDR0_ZQ" are not connected to any boundary scan cell or resource. This is the reason why the silicon nail test could not be generated.

7. In order to generate the silicon nail test for the u901 DDR3, the DDR3 library has to be modified as follows:

7.1 Change the pin usage of the group DM (u901.E07 and u901.D03) and ZQ (U901.L08) from inputs to non-digital.

7.2 Comment the vector where the DM and ZQ are declared.

```
assign CK      to pins "J07"
assign CK_     to pins "K07"
assign CKE     to pins "K09"
assign CLK     to pins "J07", "K07"

assign CS_     to pins "L02"
assign RAS_    to pins "J03"
assign CAS_    to pins "K03"
assign WE      to pins "L03"
assign COMMAND to pins "L02", "J03", "K03", "L03"
assign DM      to pins "E07", "D03"

assign BA2     to pins "M03"
assign BA1     to pins "N08"
assign BA0     to pins "M02"

assign Address to pins "N07", "R07", "L07", "R03", "T08"
assign Address to pins "R02", "R08", "P02", "P08", "N02", "P03", "P07", "N03"

assign DQ      to pins "A03", "B08", "A02", "A07", "C02", "C08", "C03", "D07"
assign DQ      to pins "H07", "G02", "H08", "H03", "F08", "F02", "F07", "E03"

assign DQS     to pins "F03", "G03", "C07", "B07"

assign VDD     to pins "B02", "D09", "G07", "K02", "K08", "N01", "N09", "R01", "R09"
assign VDDq    to pins "A01", "A08", "C01", "C09", "D02", "E09", "F01", "H02", "H09"
assign Vref    to pins "H01", "M08"

assign VSS     to pins "A09", "B03", "E01", "G08", "J02", "J08"
assign VSS     to pins "M01", "M09", "P01", "P09", "T01", "T09"
assign VSSq    to pins "B01", "B09", "D01", "D08", "E02", "E08", "F09", "G01", "G09"

assign ODT     to pins "K01"
assign ZQ      to pins "L08"
assign RES     to pins "T02"
```

```
power VDD, VDDq, VSS, VSSq, Vref

inputs CK, CK_, CKE, CS_, RAS_, CAS_, WE_, BA0, BA1, BA2 !!!DM commented DM not connected to bscan cell
inputs COMMAND
inputs Address
inputs ODT, RES !!! ZQ commented ZQ not connected to bscan cell

bidirectional DQ, DQS

nondigital NC, DM, ZQ
```

```
vector Initialize_inputs
drive DQ, DQS
set Address to "00000000000000"
set DQ to "1111111111111111"
set CK to "1"
set CK_ to "0"
set CKE to "0"
set COMMAND to "1zzz"
!!set DM to "00"
set BA0 to "0"
set BA1 to "0"
set BA2 to "0"
set DQS to "0101"
set RES to "0"
end vector

vector Keep_Control
drive DQ, DQS
set Address to "kkkkkkkkkkkkkkk"
set DQ to "kkkkkkkkkkkkkkkkk"
set CK to "k"
set CK_ to "k"
set CKE to "k"
set COMMAND to "kkkk"
!!set DM to "kk"
set BA0 to "k"
set BA1 to "k"
set BA2 to "k"
set DQS to "kkkk"
set RES to "k"
end vector
```

8. Once the DDR3 library has been modified, regenerate the silicon nail test.

Generate Tests: Generated Tests				
	Chain Name	Test Name	Test Type	Status
1	U912_U52	sn_U901	Silicon Nail	Generated



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